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Sheet	1	of	2	Attorney Docket Number	
				0756-7171	

U.S. PATENT DOCUMENTS						
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code <sup>2</sup> (if known)			
GDI		6,165,876		Yamazaki et al.	12/26/2000	
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FOREIGN PATENT DOCUMENTS							
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)			
GDI		JP	2001-144027			05/25/2001	Abst.
		JP	2002-124685			04/26/2002	Abst.
		JP	2002-083805			03/22/2002	Abst.
		JP	2002-324808			11/08/2002	U.S. equiv.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issac number(s), publisher, city and/or country where published.	T <sup>2</sup>
SDI	✓	Y. Mishima et al., "Implantation Temperature Effect on Polycrystalline Silicon by Ion Shower Doping," Journal of Applied Physics, Vol. 74, Dec. 15, 1993, No. 12, pp. 7114-7117	

Examiner Signature	<i>Stanley Isaac</i>	Date Considered	3/17/05
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		Office <sup>3</sup>	Number <sup>4</sup>				

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SDI	✓	Laviron et al., "Excimer-Laser Activation of Dopants in Silicon: A New Concept for a Uniform Treatment Over a Whole Die Area," International Workshop on Junction Technology, 2001, pp. 6-1-1 ~ 6-1-4	
SDI	✓	Specification, drawings and pending claims of U.S. Application Serial No. 09/255,777 filed February 23, 1999, entitled SEMICONDUCTOR DEVICE AND METHOD FOR FORMING THE SAME	
SDI	✓	Sasaki et al., "12.3: High Throughput CW-Laser Lateral Crystallization for Low-Temperature Poly-Si TFTs and Fabrication of 16 bit SRAMs and 270MHz Shift Registers," SID 02 DIGEST, pp. 154-157	

Examiner Signature	<i>Stanetta Baer</i>	Date Considered	3/17/05
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